

EE315 - Electronics Laboratory

Experiment - 3 Simulation

BJT Transistor and DC Biasing

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Preliminary Work

$$1 \Rightarrow \text{C-E KVL}$$

$$270 \times \beta \times i_B + 5 + 270 \times (\beta + 1) \times i_B = 10$$

$$i_B \approx 30 \mu A$$

$$\text{B-E KVL} \quad V_A = R_{DS} \times i_B$$

$$V_A + 150 \times i_B + 0.7 + 270 \times (\beta + 1) \times i_B = 10$$

$$V_A = 2.36$$

$$a \Rightarrow R_{DS} \approx 78.67 \Omega$$

$$b \Rightarrow V_{RB} = 150 \times 30 \mu = 4.5 V$$

c \Rightarrow Because when $V_{CE} = 5V$ the circuit is in Quiescent point which is in the middle point of the active mode range. $\frac{10-0}{2} = 5V$.

$$2 \Rightarrow V_{Th} = 10 \times \frac{51}{220+51} = 1.88 V$$

$$R_{Th} = 220 \parallel 51 \Omega = 41.4 \Omega$$

$$\text{B-E KVL}$$

$$V_{Th} = 41.4 \times i_B + 0.7 V + 1 \times (\beta + 1) \times i_B$$

$$I_B = 3.45 \mu A$$

$$I_C = I_B \times \beta = 1.035 \mu A$$

$$V_B = 1.88 - 41.4 \times 3.45 \mu = 1.737 V$$

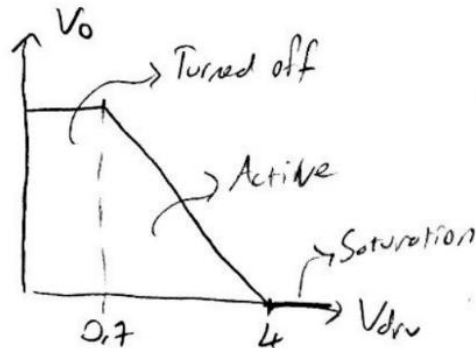
$$V_E = 1 \times I_B \times (\beta + 1) = 1.038 V$$

$$V_{CE} = 10 V - 4.7 \times I_B \times \beta - V_E = 4.088 V$$

$$3 \Rightarrow V_{CE(sat)} = 0$$

$$I_C \gg 10mA \Rightarrow I_C < \beta I_B$$

$$I_B \gg 33\mu A \text{ and } V_{drv} \gg 4 \Rightarrow \text{In Saturation}$$



$$I_B = \frac{V_{drv} - 0.7}{100\Omega}$$

$$V_O = 10 - 1k \times I_C \times \beta$$

$$V_O = \underline{\underline{12.1 - 3V_{drv}}}$$

$$4 \Rightarrow R_C \times I_{C(sat)} = 10V \Rightarrow R_C = 5k\Omega$$

$$0 \leq V_O \leq 10 \Leftrightarrow 0 \leq I_C \leq 2mA$$

$$V_{drv} = 0 \Rightarrow I_C = 0, V_O = 10V$$

$$V_{drv(max)} = R_B \times \frac{2mA}{\beta} + 0.7$$

$$R_B = \frac{9.3}{2m} \times 300 = 1.395k\Omega$$

Results

1. Build the circuit given in Figure 1.

Place an NPN transistor on the schematic and select **BC547B** as the transistor model (right-click on the transistor figure and click on "Pick New Transistor").

You will use the same transistor model for all parts of the experiment.

Place a normal resistor as R_{adj} change its value until you obtain $V_{CE} = 5\text{ V}$ with less than 1% error.

$$R_{adj} = 60.502\text{k}$$

1.a) Measure V_{BE} and the voltages across R_B , and R_C while V_{CE} is still at 5 V. Also measure I_B , I_C , and β .

$$V_{BE} = 700.60444\text{mV} \quad V_{RB} = 4.842024\text{V} \quad V_{RC} = 2.4956417\text{V}$$

$$I_B = 32.280161\mu\text{A} \quad I_C = 9.2431172\text{mA} \quad \beta = 286.34049$$

1.b) Change every one of the resistance values R_B , R_C , R_E , and transistor parameters β , and $V_{BE(on)}$ by 1% and record the new I_C values in the following table. Change only one of the resistor values or parameters at a time and keep the others at their original settings for each I_C measurement.

changed component	new value of I_C (mA)	percent change in I_C
$R_B + 1\%$	9.1998833mA	‰4.68
$R_C + 1\%$	9.2406501mA	‰0.270
$R_E + 1\%$	9.2182383mA	‰2.69
$\beta + 1\%$	9.4211837mA	‰19.25
$V_{BE(on)} + 1\%$	9.2361631mA	‰0.757

1.c) Which value(s) among R_B , R_C , R_E , β , and $V_{BE(on)}$ has/have the most significant effect on I_C ?

>>As we can see from the table above, β value has the most significant effect on I_C . Because increment on β directly increases I_C then other variables.

2.a) Build the circuit in Figure 2. Measure the values of I_B , I_C , V_B , V_{BE} , and V_{CE} .

$$I_B = 3.6623608 \mu A \quad I_C = 1.0867461 \text{ mA} \quad \beta = 296.73376$$

$$V_B = 1.7302889 \text{ V} \quad V_{BE} = 639.88048 \text{ mV} \quad V_{RC} = 5.1077065 \text{ V}$$

2.b) In practice, all component values are specified with a tolerance range. Tolerance range determines the minimum and maximum of the actual values that will be obtained if several of these components are tested. For example, a **100 k Ω** resistor with **5 %** tolerance may have an actual value between **95 k Ω** and **105 k Ω** . Similarly, the minimum and maximum values of β are given in transistor datasheets.

If thousands of this circuit are to be manufactured, then you had to make sure that V_{CE} will be reasonable within the tolerance range of all components. Indicate in the table below, which end ("min" or "max") of the tolerance range should be used for each parameter in calculation of the lowest and highest values of V_{CE} .

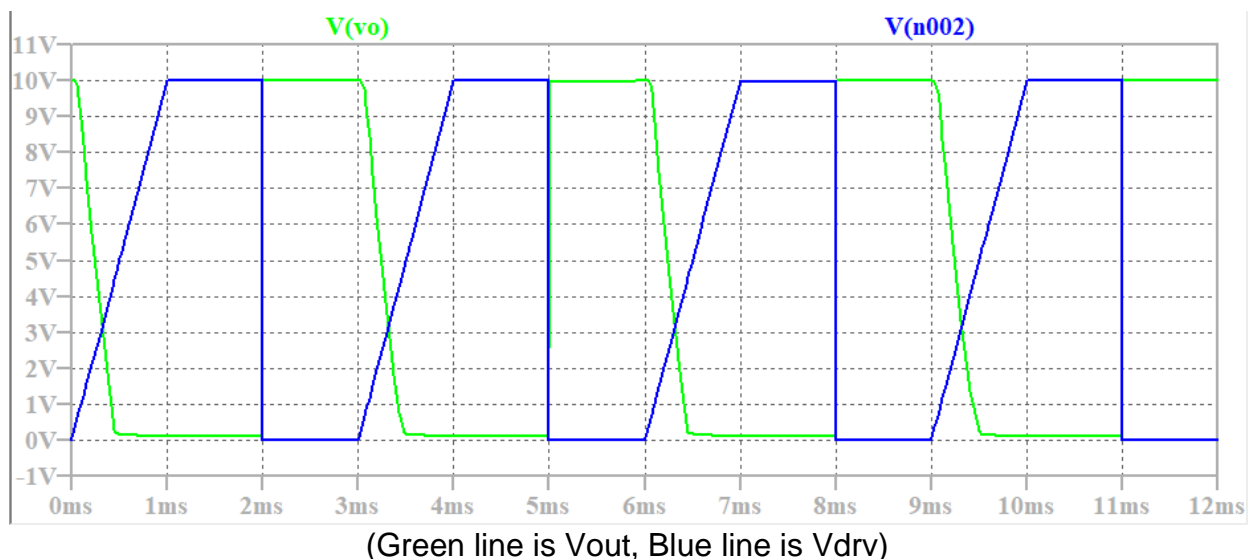
component or parameter	For lowest V_{CE}	For highest V_{CE}
R_1	min	max
R_2	max	min
R_C	max	min
R_E	min	max
β	max	min
$V_{BE(on)}$	min	max

3.a) Build the circuit given in Figure 3. Use a pulse waveform as v_{drv} that changes from **0 V** to **10 V** in **1 ms** (i.e. PULSE(0 10 0 1m 1u 1m 3m)).

3.b) Measure the range of v_{drv} values in which the transistor acts as a switch.

$$v_{drv\text{-Low-Max}} = 0 \text{ to } 839.16084 \text{ mV} \quad (\text{where } v_o > 90\% \text{ of } V_{CC})$$

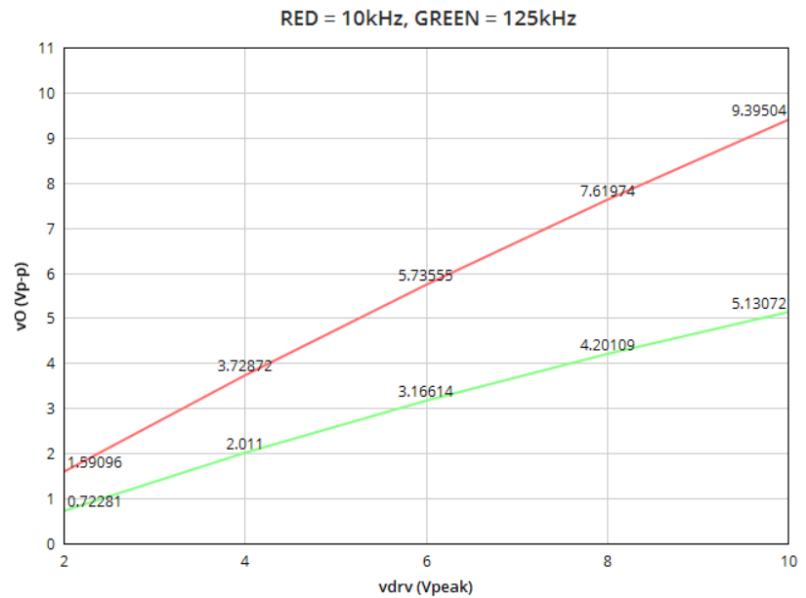
$$v_{drv\text{-High-Min}} = 3.986014 \text{ V to } 10 \text{ V} \quad (\text{where } v_o < 10\% \text{ of } V_{CC})$$



4.a) Setup the circuit in Figure 4 using the R_B and R_C values previously calculated in the preliminary work. Set v_{drv} source timing parameters to obtain a **10 kHz** pulse signal with **50 %** duty cycle (i.e. `PULSE(0 10 0 1u 1u 49u 100u)`). Keep the v_{drv} source **Trise** and **Tfall** settings at **1 μ s** all the time. Set simulation time long enough to observe the steady state v_O waveform. Change the peak voltage of v_{drv} as in the following table and record the peak-to-peak v_O voltage.

>>There is a small difference from input to output because of V_{BE} .

Freq. (kHz)	v_{drv} (Vpeak)	v_O (Vp-p)
10	2	1.59096V
	4	3.72872V
	6	5.73555V
	8	7.61974V
	10	9.39504V
125	2	0.72281V
	4	2.01100V
	6	3.16614V
	8	4.20109V
	10	5.13072V



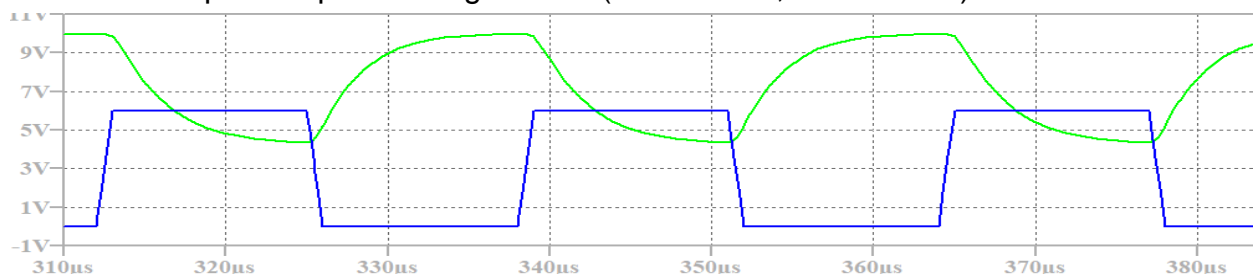
4.b) Set v_{drv} peak voltage to **10 V** and increase v_{drv} frequency (reduce **Ton** and **Tperiod**) until the peak-to-peak v_O voltage decreases down to **5 V** roughly. Make sure that duty cycle of the v_{drv} remains as **50%** while the **Trise** and **Tfall** settings are **1 μ s** all the time. Measure v_O for the other v_{drv} peak voltage settings and record the results in the table above. Plot v_O amplitude (Vp-p) versus v_{drv} (Vpeak) for the two frequency settings.

>>I plotted above with the green line.

4.c) Comment on the difference in the output signals resulting from the changes in v_{drv} peak voltage and frequency.

>>For 4a we can formulize V_o with $V_o = 10 - R_C * (V_{drv} - V_{BE}) / R_B * \beta$. Thus, when we increase the peak to peak voltage of V_{drv} , We obtain greater range of V_o which is the same thing as $V_{o(peak-peak)}$. Due to this relationship, peak to peak voltage of V_o and V_{drv} are inversely proportional.

On the other hand, transistors are not responding to the signal instantaneously as we can see below. That's why, when we increase the frequency of V_{drv} , we are able to decrease the peak to peak voltage of V_o . (Green = V_o , Blue = V_{drv})



Conclusion

>>In the first experiment, we figured out how to measure the various values on the transistor circuit and we saw which variable has the most significant effect on the collector current.

In the second experiment, we find out how components values affects the V_{CE} value. The relationship is proportional, for lowest V_{CE} value, we need the lowest value of the component. However, if it is inversely proportional, the relationship is exactly the opposite. This improved our approach on tolerance values.

In the third experiment, we observed the relation between V_{drv} and V_{cc} on transistor switch circuit.

In the last experiment, we saw how a frequency and peak to peak voltage of V_{drv} affects the behavior of the V_o . We observed that the bjt transistor has a switching speed which is called slew rate and it acts as a capacitor. It is more observable when we have high output impedance. When the driving signal is applied to the transistor input, some time is needed to charge the emitter-junction transition capacitance. Because of this delay time or transit time, we saw smaller peak to peak V_o voltage when there is high frequency.